

EEC 116 Lecture #4: CMOS Inverter AC Characteristics

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Acknowledgments

- **Slides due to Rajit Manohar from ECE 547
Advanced VLSI Design at Cornell University**

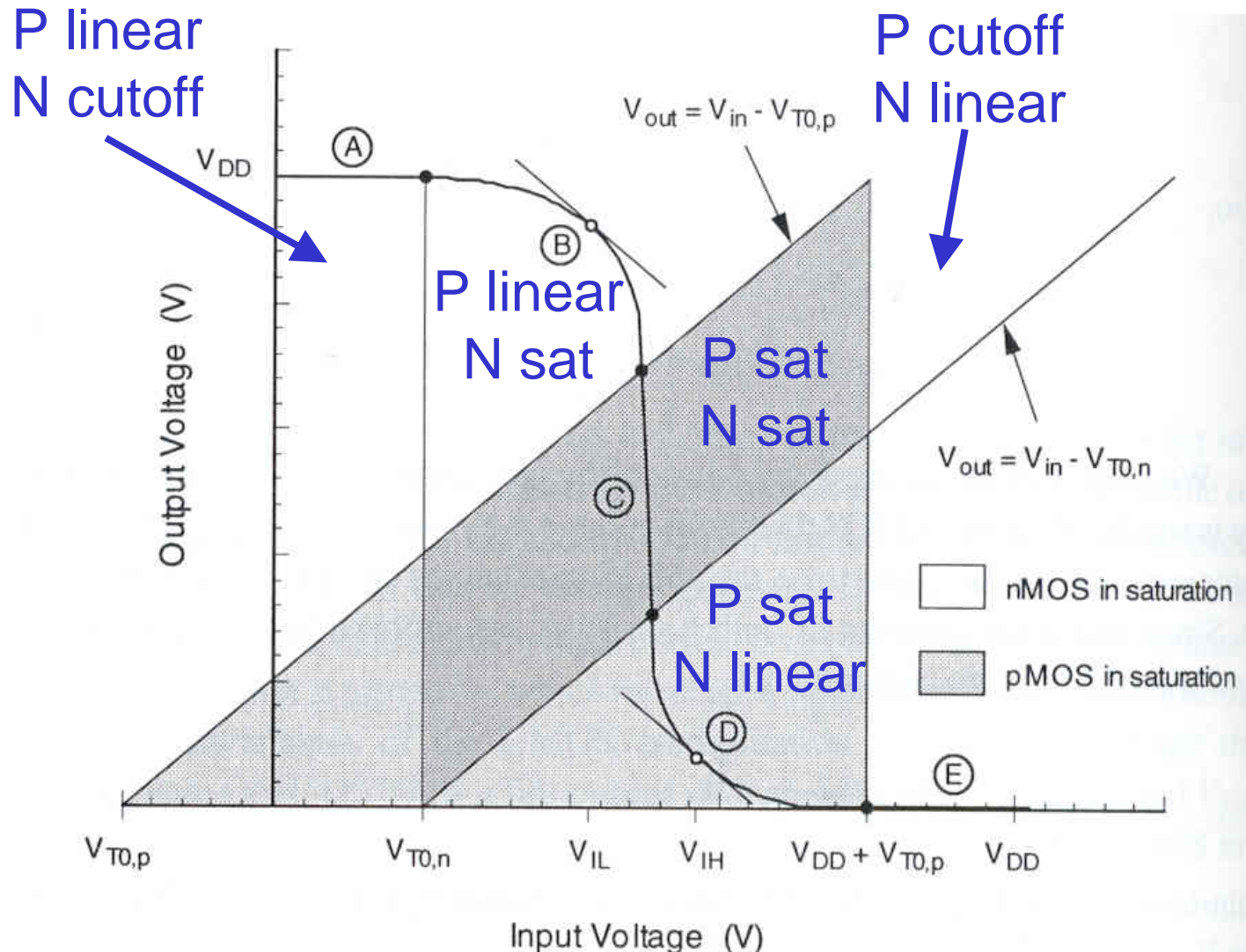
Announcements

- **Lab 2 this week, report due next week**
- **Quiz 1 on Monday!**

Outline

- **Review: CMOS Inverter Transfer Characteristics**
- **Finish Lecture 3 slides**
- **CMOS Inverters: Rabaey 5.4-5.5 (Kang & Leblebici, 6.1-6.4, 6.7)**

CMOS Inverter VTC: Device Operation



Logic Circuit Delay

- For CMOS (or almost all logic circuit families), only one fundamental equation necessary to determine delay:

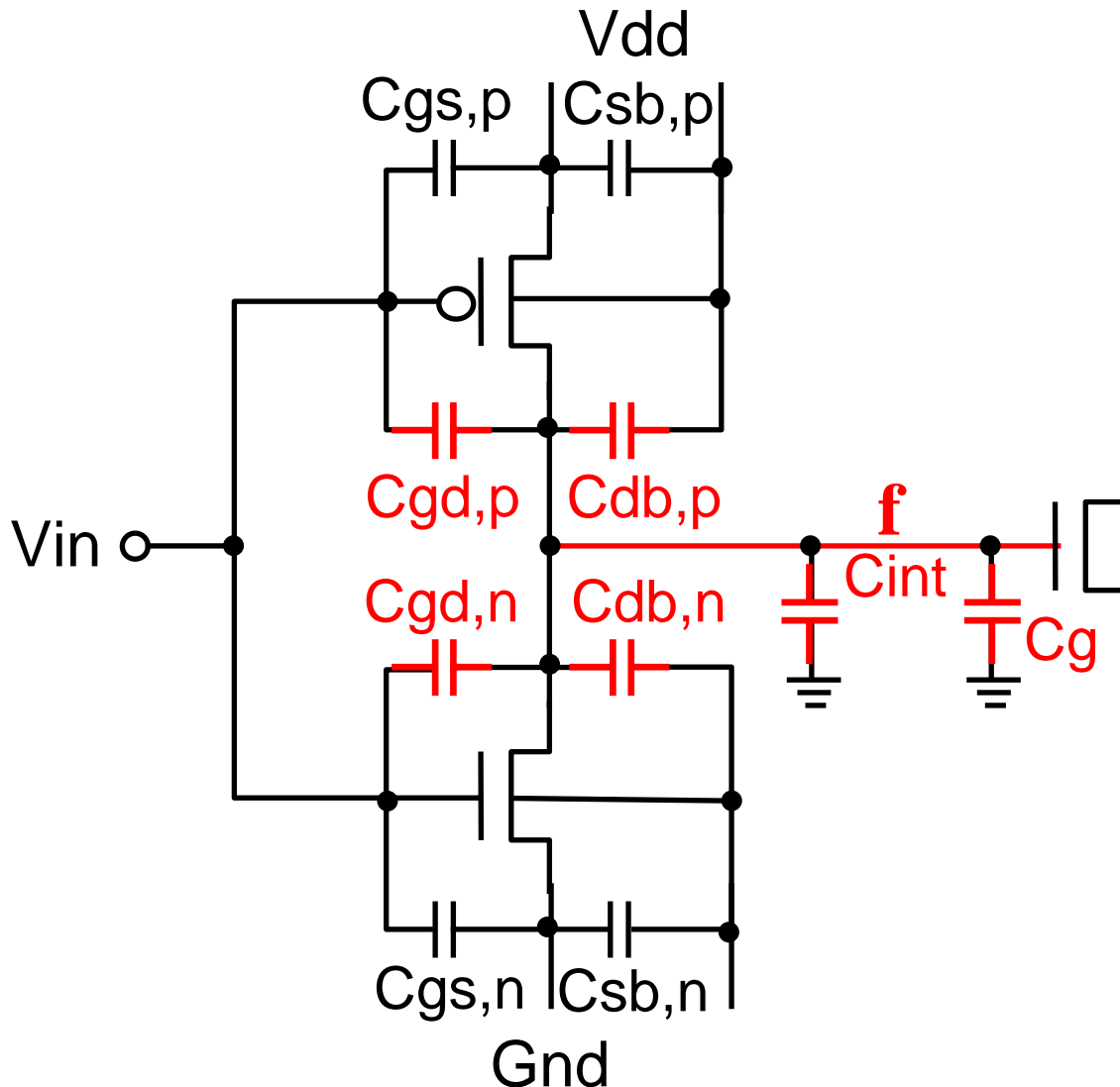
$$I = C \frac{dV}{dt}$$

- Consider the discretized version: $I = C \frac{\Delta V}{\Delta t}$

- Rewrite to solve for delay: $\Delta t = C \frac{\Delta V}{I}$

- Only three ways to make faster logic: $\downarrow C, \downarrow \Delta V, \uparrow I$

CMOS Inverter Capacitances



- Assume input transition is fixed, then delay determined by output

Capacitance on node f (output):

- Junction cap
Cdb,p and Cdb,n
- Gate capacitance
Cgd,p and Cgd,n
- Interconnect cap
- Receiver gate cap

CMOS Inverter Junction Capacitances

- Junction capacitances $C_{db,p}$ and $C_{db,n}$:

– Equation for junction cap:

$$C_j(V) = \frac{AC_{j0}}{\left(1 - \frac{V}{\phi_0}\right)^m}, \quad C_{j0} = \left(\frac{\epsilon q}{2} \frac{N_a N_d}{N_a + N_d} \frac{1}{\phi_0}\right)^m$$

- Non-linear, depends on voltage across junction
- Use K_{eq} factor to get equivalent capacitance for a voltage transition

$$C_{db} = AK_{eq}C_j + PK_{eqsw}C_{jsw}$$

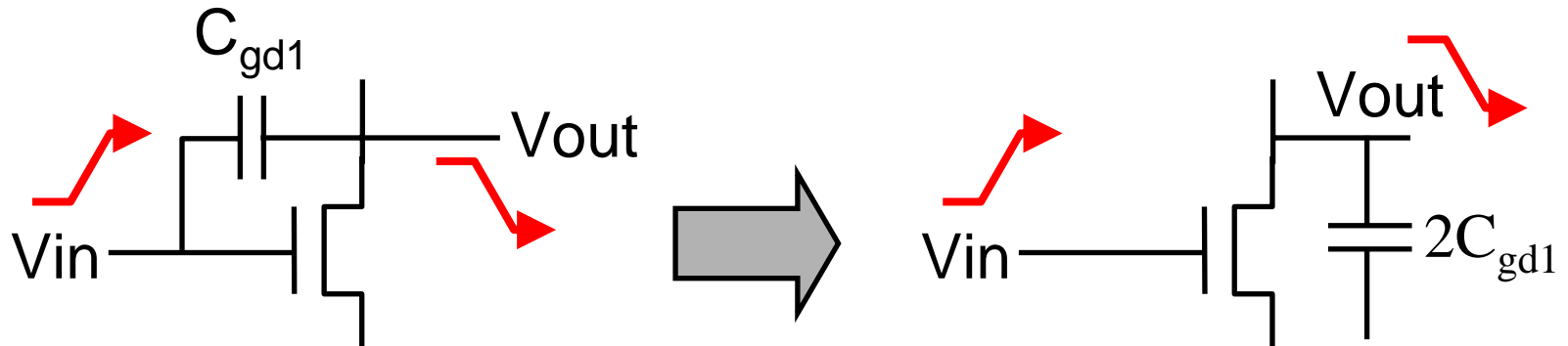
CMOS Inverter Gate Capacitances

- Gate capacitances $C_{GD,p}$ and $C_{GD,n}$:
 - Just after the input switches ($t = 0^+$), what regions are transistors in?
 - One is in cutoff: $C_{GD} = \text{Overlap Cap}$
 - One is in Saturation: $C_{GD} = \text{Overlap Cap}$
 - Therefore, gate-to-drain capacitance is due to overlap capacitance :

$$C_{gd,p} = C_{gd,n} = C_{ox} W L_D$$

However, also need to consider Miller effect ...

CMOS Inverter Capacitances: Miller Effect



- **When input rises by ΔV , output falls by ΔV**

- Change in stored charge: $\Delta Q = C_{gd1}\Delta V - (-C_{gd1}\Delta V)$
- Effective voltage change across C_{gd1} is $2\Delta V$
- Effective capacitance to ground is *twice* C_{gd1}

- **Including Miller effect:**

$$C_{gd,p} = C_{gd,n} = 2C_{ox}WL_D \quad (\text{For transistor in Cutoff})$$

CMOS Inverter Capacitances: Receiver

- **Receiver gate capacitance**

- Includes all capacitances of gate(s) connected to output node
- Unknown region of operation for receiver transistor: total gate cap varies from $(2/3)WLC_{ox}$ to WLC_{ox}
- Ignore Miller effect (taken into account on output)
- Assume worst-case value, include overlap

$$C_g = WL_{eff} C_{ox} + 2WL_D C_{ox}$$

$$C_g = WL C_{ox}$$

Inverter Capacitances: Analysis

- **Simplify the circuit: combine all capacitances at output into one lumped linear capacitance:**

$$C_{\text{load}} = 2 * C_{\text{gd},n} + 2 * C_{\text{gd},p} + C_{\text{db},n} + C_{\text{db},p} + C_{\text{int}} + C_{\text{g}}$$

↙ ↘
Miller effect

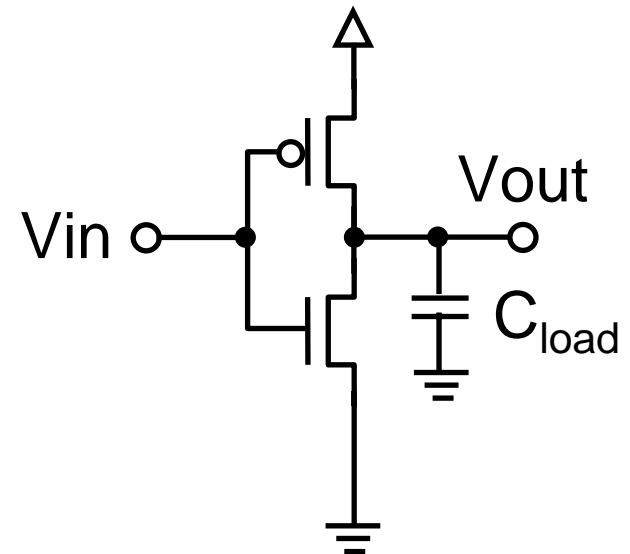
- **$C_{\text{sb},n} = C_{\text{sb},p} = 0$**
- **$C_{\text{gs},n}$ and $C_{\text{gs},p}$ are not connected to the load. These are part of the gate capacitance C_{g}**

First-Order Inverter Delay

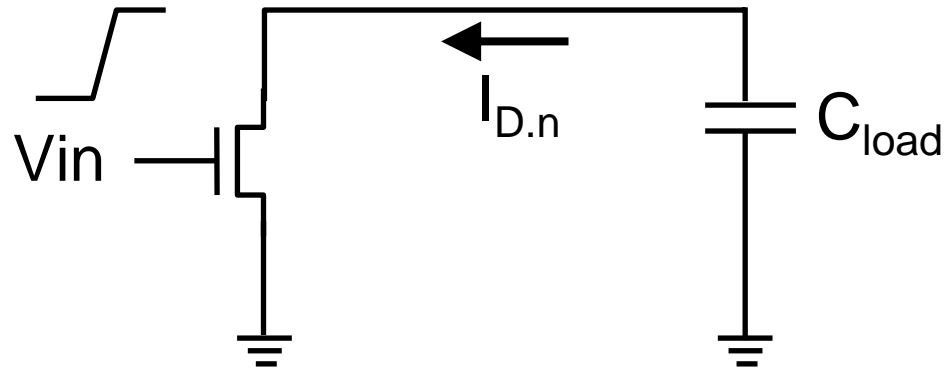
- Suppose ideal voltage step at input
- Assume: Current charging or discharging capacitance C_{load} is nearly constant I_{avg}

- $t_{PHL} = C_{load} (V_{dd} - V_{dd}/2) / I_{avg}$

- $t_{PLH} = C_{load} (V_{dd}/2 - V_{ss}) / I_{avg}$



Inverter Delay: Falling

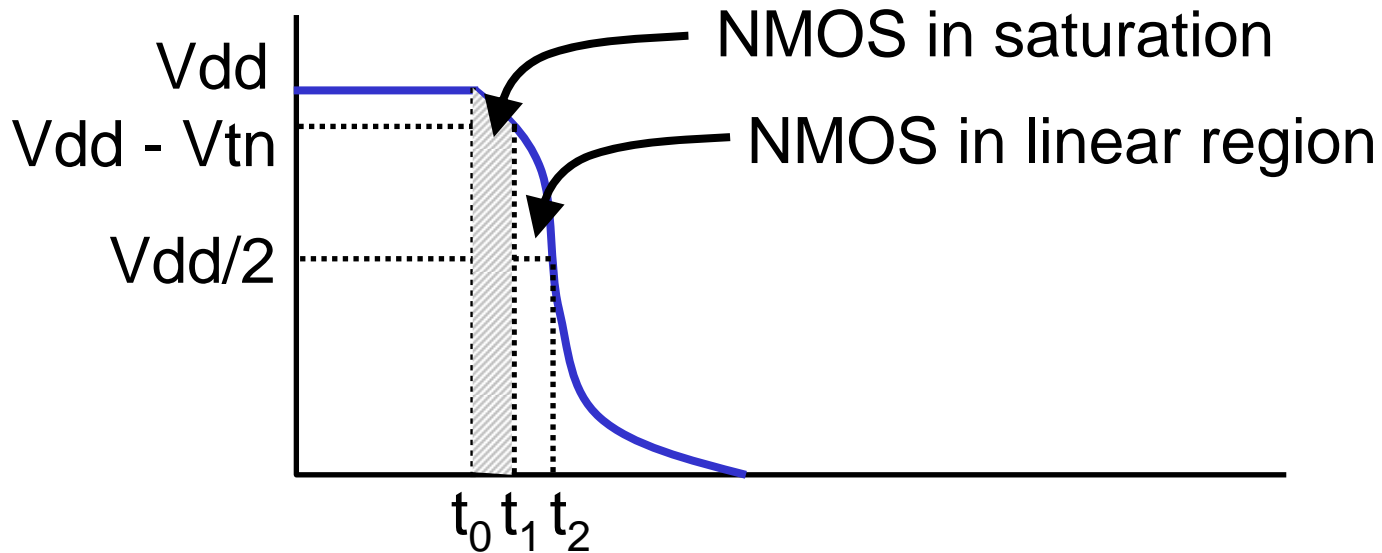


- Assume PMOS fully off (ideal step input, $I_{D,p} = 0$)

$$I = C \frac{dV}{dt}$$

$$I_{D,n} = C_{load} \frac{dV_{out}}{dt} \quad \Rightarrow \quad \text{Need to determine } I_{D,n}$$

Inverter Delay: Falling



- From t_0 to t_1 : NMOS in saturation
- From t_1 to t_2 : NMOS in linear region
- Find I_D in each region

Inverter Delay: Falling t_1-t_0

- **Assumption: Input fast enough to go through transition before output voltage changes**
- **V_{out} drops from V_{OH} to $V_{DD}-V_{TN}$ (NMOS saturated)**

$$I_{DS} = k_n (V_{in} - V_{T0,n})^2 / 2 = k_n (V_{OH} - V_{T0,n})^2 / 2$$

$$\int_{t_0}^{t_1} dt = \frac{-2C_L}{k_n (V_{OH} - V_{T0,n})^2} \int_{V_{OH}}^{V_{OH}-V_{T0,n}} dV_{out}$$

$$t_1 - t_0 = \frac{2C_L V_{T0,n}}{k_n (V_{OH} - V_{T0,n})^2}$$

Inverter Delay: Falling t_2-t_1

- V_{out} drops from $(V_{OH}-V_{T0,n})$ to $V_{DD}/2$
- NMOS in linear region

$$I_{DS} = k_n \left[(V_{OH} - V_{T0,n}) V_{out} - \frac{1}{2} V_{out}^2 \right]$$

$$t_2 - t_1 = -C_L \int_{V_{OH}-V_{T0,n}}^{(V_{OH}+V_{OL})/2} \frac{dV_{out}}{k_n \left[(V_{OH} - V_{T0,n}) V_{out} - \frac{1}{2} V_{out}^2 \right]}$$

$$t_2 - t_1 = \frac{C_L}{k_n (V_{OH} - V_{T0,n})} \ln \left[\frac{2(V_{OH} - V_{T0,n}) - (V_{OH} + V_{OL})/2}{(V_{OH} + V_{OL})/2} \right]$$

Inverter Delay: Falling, Total

- Total fall delay = $(t_1 - t_0) + (t_2 - t_1)$

$$t_{PHL} = \frac{C_L}{k_n (V_{OH} - V_{T0,n})} \left[\frac{2V_{T0,n}}{V_{OH} - V_{T0,n}} + \ln \left(\frac{4(V_{OH} - V_{T0,n})}{V_{OH} + V_{OL}} - 1 \right) \right]$$

Inverter Delay: Rising

- Similar calculation as for falling delay
- Separate into regions where PMOS is in linear, saturation

$$t_{PLH} = \frac{C_L}{k_p (V_{OH} - V_{OL} - |V_{T0,p}|)} \left[\frac{2|V_{T0,p}|}{V_{OH} - V_{OL} - |V_{T0,p}|} + \ln \left(\frac{4(V_{OH} - V_{OL} - |V_{T0,p}|)}{V_{OH} + V_{OL}} - 1 \right) \right]$$

- **Note:** to balance rise and fall delays (assuming $V_{OH} = V_{DD}$, $V_{OL} = 0V$, and $V_{T0,n} = V_{T0,p}$) requires

$$\frac{k_p}{k_n} = 1 \quad \left(\frac{W}{L} \right)_p = \frac{\mu_n}{\mu_p} \approx 2.5$$

Inverter Rise, Fall Times

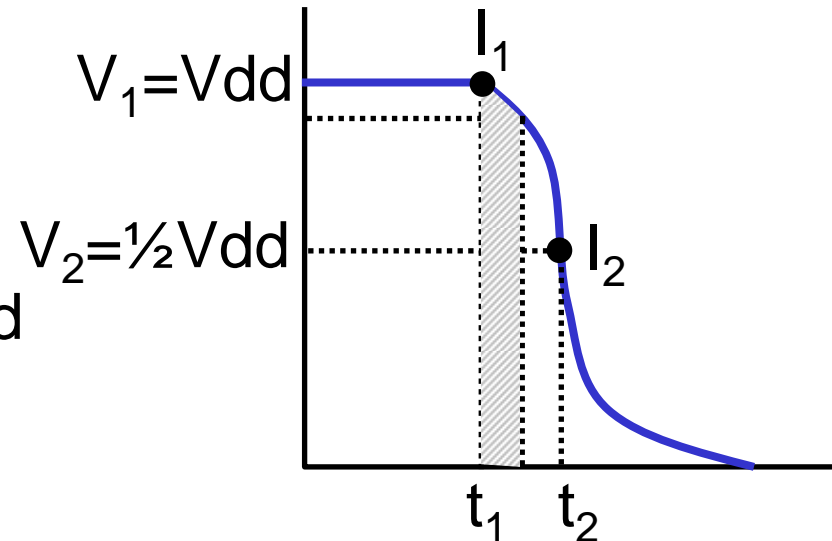
- **Summary -- Exact method: separate into two regions**
 - t_1
 - V_{out} drops from $0.9V_{DD}$ to $V_{DD}-V_{T,n}$ (NMOS in saturation)
 - V_{out} rises from $0.1V_{DD}$ to $|V_{T,p}|$ (PMOS in saturation)
 - t_2
 - V_{out} drops from $V_{DD}-V_{T,n}$ to $0.1V_{DD}$ (NMOS in linear region)
 - V_{out} rises from $|V_{T,p}|$ to $0.9V_{DD}$ (PMOS in linear region)
 - $t_{f,r} = t_1 + t_2$

CMOS Inverter Delay

- Review of approximate method
 - Assume a constant average current for the transition
 - I_{avg} = average of drain current at beginning and end of transition

$$t_{PHL} = \frac{C_{load}}{I_{avg}} \left(V_{DD} - \frac{1}{2} V_{DD} \right)$$

$$t_{PLH} = \frac{C_{load}}{I_{avg}} \left(\frac{1}{2} V_{DD} - V_{SS} \right)$$



$$I_{avg} = \frac{1}{2}(I_1 + I_2)$$

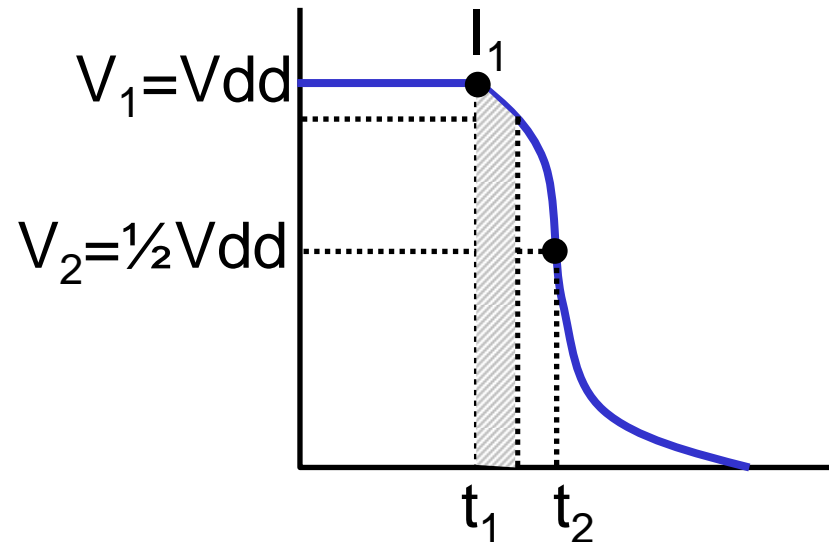
CMOS Inverter Delay: 2nd Approximation

- Another approximate method:
 - Again assume constant I_{avg}
 - I_{avg} = current I_1 at start of transition

$$t_{PHL} = \frac{C_{load} V_{DD}}{k_n (V_{DD} - V_{Tn})^2}$$

$$t_{PLH} = \frac{C_{load} V_{DD}}{k_p (V_{DD} - |V_{TP}|)^2}$$

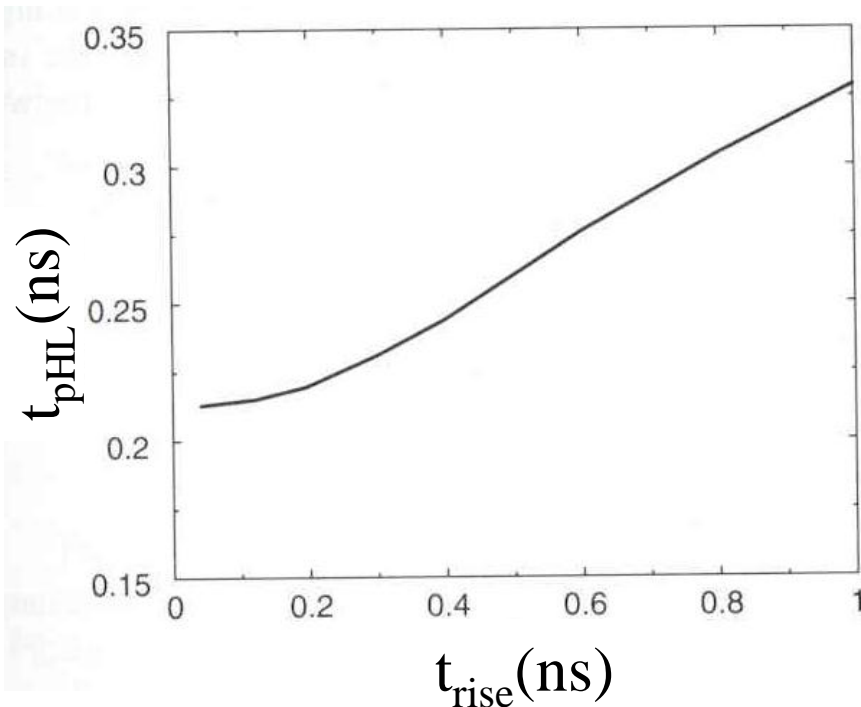
- Why is this a good approximation (esp. for deep submicron)?



$$I_{avg} = I_1$$

CMOS Inverter Delay: Finite Input Transitions

- What if input has finite rise/fall time?
 - Both transistors are on for some amount of time
 - Capacitor charge/discharge current is reduced



Empirical equations:

$$t_{pHL}(actual) = \sqrt{t_{pHL}^2(step) + \left(\frac{t_r}{2}\right)^2}$$

$$t_{pLH}(actual) = \sqrt{t_{pLH}^2(step) + \left(\frac{t_f}{2}\right)^2}$$

How to Improve Delay?

- **Minimize load capacitances**
 - Small interconnect capacitance
 - Small C_g of next stage
- **Raise supply voltage**
 - Increases current faster than increased swing ΔV
- **Increase transistor gain factor**
 - Increase transistor drive current for charging/discharging output capacitance
- **Use low threshold voltage devices**
 - More subthreshold leakage power dissipation

Inverter Power Consumption

- **Static power consumption (ideal) = 0**
 - Actually DIBL (Drain-Induced Barrier Lowering), gate leakage, junction leakage are still present
- **Dynamic power consumption**

$$P_{avg} = \frac{1}{T} \int_0^T v(t)i(t)dt$$
$$P_{avg} = \frac{1}{T} \left[\int_0^{T/2} V_{out} \left(-C_{load} \frac{dV_{out}}{dt} \right) dt + \int_{T/2}^T (V_{DD} - V_{out}) \left(C_{load} \frac{dV_{out}}{dt} \right) dt \right]$$
$$P_{avg} = \frac{1}{T} \left[\left(-C_{load} \frac{V_{out}^2}{2} \right) \Big|_0^{T/2} + \left(V_{DD} V_{out} C_{load} - \frac{1}{2} C_{load} V_{out}^2 \right) \Big|_{T/2}^T \right]$$
$$P_{avg} = \frac{1}{T} C_{load} V_{DD}^2 = C_{load} V_{DD}^2 f$$

Next Time: Combinational Logic and Layout

- **Combinational MOS Logic**
 - DC Characteristics, Equivalent Inverter method
 - AC Characteristics, Switch Model
- **Combinational Logic Layout**